#### An Organic FET SRAM for Braille Sheet Display with Back Gate to Increase Static Noise Margin

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#### Outline

- Large Area Electronics Using Organic FETs
- Braille Sheet Display (BSD)
- Key Circuit Technologies for BSD
  - (1) 5-transistor SRAM Cells and Pipelining for Write-Operation
  - (2) Control of SRAM Static Noise Margin with A Back Gate

(3) Overdrive Techniques for Driver Transistors



# **Organic FETs (OFETs)**

	OFETs	Si MOSFETs
Design rule	<b>50</b> μm	90 nm
Hardness	Flexible (a)	Solid
Drive current	25 nA / μm @ 40 V	1 mA / μm @ 1 V
Gate delay	0.3 ms	10 ps
Cost / area	Low (b)	High
Cost / transistor	High	Low
Lifetime	Days	Years

#### ➡

What is the application of OFETs that utilizes (a) and (b)?

### Large Area Electronics

 Functional units are distributed on a square, 10 cm – 10 m on a side.

#### **Pressure sensors + OFETs Photodetectors + OFETs**





#### Artificial skin (ISSCC2004)



#### Scanner (ISSCC2005)

#### This work



#### Actuators + OFETs Braille display

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Summary

#### **Plastic Actuators**



## **Developed Braille Sheet Display**



6 x 4 Braille characters

Each Braille character consists of 2 x 3 dots, and the display has a total of 144 dots.



#### **Device Structures**



# Why SRAM?



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#### **Unit Circuit for An Actuator**



# **5-Tr SRAM Cell**



Compared with the conventional 6-Tr SRAM cell, 5-Tr SRAM cell reduces the cell area by 20%.

#### **Issue of 5-Tr SRAM Cell**



# **Pipelining for Write-Operation**

Design target for the write-time of the whole SRAM (= 144 cells) is within 2 s.



The slow transition time can be hidden by pipelining the write-operation.

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#### **PMOS OFET with Back Gate**



The V<sub>TH</sub> control technology using a back gate compensates for the immature V<sub>TH</sub> control process technology and achieves a reliable SRAM operation.

#### **Butterfly Curves of SRAM**



#### Static Noise Margin (SNM) of SRAM



### **Chemical Degradation of OFETs**



• OFETs are chemically degraded by the oxygen and the moisture in the atmosphere.

The most serious problem with OFETs

### Aging of Inverter in SRAM



### **Compensation for Aging**



# Aging of SNM and Compensation



• A constant SNM can be achieved with the back gate.

The proposed compensation technology is essential to OFET applications.

 Manufacturing variation can also be compensated.

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#### **Overdrive Techniques for Driver**



#### **Operation of Braille Sheet Display**



#### **Summary of Speeding Up Braille Sheet Display**



Developed circuit technologies increased the speed of the Braille sheet display 1580 times, and achieved the practical 3.1-ns operation.

# Summary

- OFETs were integrated with actuators, and a Braille sheet display was demonstrated.
- Pipelining the write-operation reduced the SRAM writetime by 74%.
- Threshold voltage control technology using a back gate increased the SNM of SRAM from 2.5 V to 5.9 V and successfully compensated for the chemical degradation of the OFETs after 15 days.
- The overdrive techniques for the driver OFETs reduced the transition time of the actuator from 34 s to 2 s.
- These developed circuit technologies will be essential for the future large area electronics made with OFETs.